

2012 IEEE International Test Conference

(ITC 2012)

**Anaheim, California, USA
5 – 8 November 2012**



**IEEE Catalog Number: CFP12ITC-PRT
ISBN: 978-1-4673-1594-4**

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





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


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
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ITC 2011 Best Paper

Real-Time Testing Method for 16-Gbps 4-PAM Signal Interface I G
M. Ishida, K. Ichiyama, D. Watanabe, M. Kawabata, T. Okayasu

*Presented at ITC, but not included in proceedings